

Atty.  
Dkt. No.

M#

Client Ref.

284101

OSP-11726

Applicant: HASEGAWA et al.

Appln. No.: DIV. of 09/651,255

Filing Date: Herewith

Examiner: Pert, F.

Group Art Unit: 2813

**INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT**

Date: December 19, 2001

Page

1

of

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**U.S. PATENT DOCUMENTS**

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
	AR					
	BR					
	CR					
	DR					
	ER					
	FR					
	GR					
	HR					
	IR					
	JR					
	KR					
	LR					
	MR					
	NR					

**FOREIGN PATENT DOCUMENTS**

		Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract		Translation Readily Available	
						Enclosed	No	Enclose	No
UK	OR	5-99845	04/1993	Japan	TAKEUCHI et al.	X			X
1	PR	11-57390	03/1999	Japan	SHIRAI et al.	X			X
1	QR	99/30809	06/1999	WIPO	OHMI	X			X
1	RR	11-183366	07/1999	Japan	SATO et al.	X			X
UK	SR	968 753	01/2000	Europe	OHMI et al.				
	TR								
	UR								
	VR								

**OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)**

UK	WR	Masusaki et al., Nippon Sanso Giho (Nippon Sanso Technical Reports), "Monitoring of Impurities in Si Epitaxial Gases by Use of Near-Infrared Laser Diode Spectroscopy," December 3, 1999, No. 18, pp. 32-33			
UK	XR	Microsystem Technology Laboratories Annual Report, Massachusetts Institute of Technology, May 1999			
	YR				
	ZR				
	AAR				
	BBR				

Examiner

Date Considered: 7/6/99

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.



Atty. Dkt. No.	M#	Client Ref.
	284101	OSP-11726

**INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT**

Applicant: HASEGAWA et al.

Appln. No.: 10/021,259

Filing Date: December 19, 2001

Date: February 14, 2003

Page 1 of 1

Examiner: Unknown

Group Art Unit: Unknown

**U.S. PATENT DOCUMENTS**

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
IAE	AR 6,197,699 B1	03/2001	Fritzinger et al.	438	710	
IAE	BR 4,847,512	07/1989	Seta	250	575	
	CR					
	DR					
	ER					
	FR					
	GR					
	HR					
	IR					
	JR					
	KR					
	LR					
	MR					
	NR					

**FOREIGN PATENT DOCUMENTS**

	Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract		Translation Readily Available	
					Enclosed	No	Enclose	No
IAE	OR JP10125609A	05/1998	Japan	Koji	X			
IAE	PR WO99/34192A	07/1999	WIPO	Satoh et al.	X			
IAE	QR JP6186149	07/1994	Japan	Hasegawa et al.	X			
	RR							
	SR							
	TR							
	UR							
	VR							
	WR							
	XR							

**OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)**

YR	
ZR	
AAR	
BBR	
CCR	
DDR	

Examiner

Date Considered: 7/6/03

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re PATENT APPLICATION of

Inventor(s): HASEGAWA et al.

Atty. Dkt: 61063/284101

Appln. No.: 10/021,259

Fil d: December 19, 2001

FOR: METHOD OF PURGING CVD APPARATUS AND METHOD FOR JUDGING  
MAINTENANCE OF TIMES OF SEMICONDUCTOR PRODUCTION APPARATUSES

Group Art Unit: Unknown

Examiner: Unknown

Unknown

Unknown

2651  
#3  
#6/IDS  
3/20/03  
Hayes



Date: February 25, 2002

**IDS LETTER CITING APPLICATION(S)**

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FEB 27 2002

**GROUP 3600**

The Examiner's attention is directed to the following application(s) of:

Examiner's Initials*	FIRST INVENTOR (Last Name Only)	APPLICATION NO. & Filing Date	ENCLOSED
LAK	OMI	09/096,986 June 12, 1998	<input checked="" type="checkbox"/> Spec <input checked="" type="checkbox"/> Drawings <input checked="" type="checkbox"/> Original Claims <input checked="" type="checkbox"/> Other Abstract
		now 6,431,353	<input type="checkbox"/> Spec <input type="checkbox"/> Drawings <input type="checkbox"/> Current Claims <input type="checkbox"/> Other
			<input type="checkbox"/> Spec <input type="checkbox"/> Drawings <input type="checkbox"/> Current Claims <input type="checkbox"/> Other

**PLEASE DO NOT PRINT** the above information on the patent which results from the subject application.

This IDS is being filed within 3 months of the filing date of this application, and hence this IDS must be considered per Rule 97(b)(1).

Consideration of each listed application is earnestly solicited since unpublished patent applications are contemplated as IDS material; see the exception in Rule 98(a)(2)(iii) and note the penultimate sentence of MPEP 609.

Further, in keeping with MPEP 609, Subsec. C(2), 2nd para., line 10 to end of the paragraph (especially note lines 18-25) **PLEASE RETURN A COPY OF THIS LETTER** with the Examiner's initials adjacent each above listing so that applicant will know that each listed application has been considered as required by PTO policy. Thanks.

Respectfully submitted

*[Signature]*

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*Li Als*  
*7/6/4*  
*Considered*

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\*The Examiner's initials adjacent a citation indicates he/she has considered the cited application relative to the subject application.



PTO/SB/08a (05-03)

Approved for use through 04/30/2003. OMB 0651-0031

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Substitute for form 1449A/PTO

**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Sheet 1 of 1

**Complete If Known**

Application Number	10/021,259
Filing Date	12/19/2001
First Named Inventor	HASEGAWA et al.
Art Unit	2829
Examiner Name	Pert, E.
Attorney Docket Number	061063-0284101

**U. S. PATENT DOCUMENTS**

Examiner Initials*	Cite No. <sup>1</sup>	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code <sup>2</sup> (if known)			
		US-			
		US-			
		US-			
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**FOREIGN PATENT DOCUMENTS**

Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>6</sup>
		Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)				
AK	1	JP 10-144581	05/29/1998	Masanori		X
	2	JP 2-176391	07/09/1990	Mitsuo et al.		X
	3	JP 5-099845	04/23/1993	Nobuo et al.		X
AK	4	JP 10-3352 49	12/18/1998	Imran		X

Examiner Signature	<i>Zi Ali</i>	Date Considered	7/6/9
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\*EXAMINER: Initial if reference considered. Whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. <sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> See Kinds Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov) or MPEP 901.04. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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